

## Corrigendum

# Corrigendum to “A New Iterative Algorithm Based on Correction of Sensitivity Matrix for Electrical Resistance Tomography”

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In the article titled “A New Iterative Algorithm Based on Correction of Sensitivity Matrix for Electrical Resistance Tomography” [1], there was an error in the “Introduction” section, where “ERT has been widely used for chemical [2], food processing [3], biology [4], geology [5], and other industrial applications [6]” should be corrected to “ERT has been widely used for chemical [2], thin films characterization [3], biology [4], geology [5], and other industrial applications [6].”

## References

- [1] Y. Chen, Y. Han, W. Yang, and K. Li, “A New iterative Algorithm based on correction of sensitivity Matrix for electrical resistance Tomography,” *Mathematical Problems in Engineering*, vol. 2019, Article ID 6384132, 15 pages, 2019.